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Substitute for form 1449/PTO (Revised 04/2003)				Complete if Known	
				Application Number	PCT/GB2003/002599
				Filing Date	06/17/2003
				First Named Inventor	Hamilton
				Group Art Unit	Unknown
				Examiner Name	Unknown
Sheet	1	of	2	Attorney Docket Number	031749/286126

## U. S. PATENT DOCUMENTS

Examiner Initials*	Cite No.	Document Number Number - Kind Code (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages of Relevant Figures Appear
pmc	1	US-5,694,356	12/02/1997	Wong et al.	
pmc	2	US-5,745,409	04/28/1998	Wong et al.	
pmc	3	US-5,748,124	05/05/1998	Rosenthal et al.	
pmc	4	US-5,793,778	08/11/1998	Qureshi	
		US-			

## FOREIGN PATENT DOCUMENTS

Examiner Initials	Cite No.	Foreign Patent Document Country Code - Number Kind Code (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	English Language Translation Attached
pmc	5	WO 98/55880	12/10/1998	Hamida et al.		
Examiner Signature				Date Considered	1/11/06	

\*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

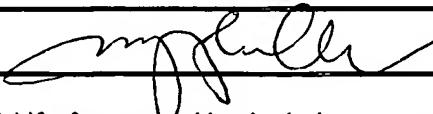
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## OTHER DOCUMENTS

Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	English Language Translation Attached
gme	6	ZHENG ET AL.; <i>A Novel Test Generation Approach for Parametric Faults in Linear Analog Circuits</i> ; 14th IEEE VLSI Test Symposium; 1996; Pages 470-475 (XP-002265465)	
gme	7	SAAB ET AL.; <i>CRIS: A Test Cultivation Program for Sequential VLSI Circuits</i> ; IEEE; 1992; Pages 216-219	
gme	8	VAN SPAANDONK ET AL.; <i>Selecting Measurements to Test the Functional Behavior of Analog Circuits</i> ; Journal of Electronic Testing: Theory and Applications; 1996; Pages 9-18; Vol. 9; Kluwer Academic Publishers, The Netherlands (XP-000636621)	
gme	9	BALIVADA ET AL.; <i>A Unified Approach for Fault Simulation of Linear Mixed-Signal Circuits</i> ; Journal of Electronic Testing: Theory and Applications; 1996; Pages 29-41; Vol. 9; Kluwer Academic Publishers, The Netherlands (XP-000636623)	
gme	10	SOUDERS, ET AL., <i>Accurate Frequency Response Determinations from Discrete Step Response Data</i> ; IEEE Transactions on Instrumentation and Measurement; June 1987; Pages 433-439; Vol. IM-36, No. 2	
gme	11	ECKERSALL, ET AL., <i>Testing an Analogue Circuit Using a Complementary Signal Set</i> ; IEE Colloquium on "Testing Mixed Signal Circuits, 1992; Pages 5/1-5/6; Digest No. 1992/118	
gme	12	AL-QUTAYRI, ET AL., <i>Go/no-go Testing of Analogue Macros</i> ; IEE Proceedings; August 1992; Pages 534-540; Vol. 139, No. 4	
gme	13	PAN, ET AL.; <i>Pseudorandom Testing for Mixed-Signal Circuits</i> ; IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems; October 1997; Pages 1173-1185; Vol 16, No. 10	
gme	14	VARIYAM, ET AL.; <i>Digital-Compatible BIST for Analog Circuits Using Transient Response Sampling</i> ; IEEE Design & Best of Computers; July-September 2000; Pages 106-115;	
gme	15	Hooke, ET AL.; <i>"Direct Search" Solution of Numerical and Statistical Problems</i> ; May 1960, revised October 1960; Pages 212-229; Westinghouse Research Laboratories; Pittsburgh, Pennsylvania	
gme	16	Copy of Search Report for International Application No. PCT/GB03/02599 completed April 20, 2004	
gme	17	Copy of International Preliminary Examination Report for International Application No. PCT/GB03/02599 completed November 2, 2004	

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